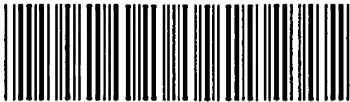


Search Notes

Application/Control No.

10/632,011

Examiner

Hai C. Pham

Applicant(s)/Patent under
Reexamination

SUBIRADA ET AL.

Art Unit

2861

SEARCHED

Class	Subclass	Date	Examiner
347	15, 19, 107, 116- 117	7/2/2005	HP

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	7/2/2005	HP